

Notice of References Cited	Application/Control No. 10/628,150		Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner Anh T. Mai		Art Unit 2832	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0036561 a1	03-2002	Jedlitschka, Hans	336/232
*	B	US-6,724,290	04-2004	Ohnmacht et al.	336/200
*	C	US-5,604,352	02-1997	Schuetz, Marlin N.	250/492.3
*	D	US-5,565,837	10-1996	Godek et al.	336/232
*	E	US-5,529,831	06-1996	Waga et al.	428/209
*	F	US-2003/0231093 a1	12-2003	Hsu et al.	336/200
*	G	US-6,287,932	09-2001	Forbes et al.	438/381
*	H	US-6,798,039	09-2004	Gillespie et al.	257/531
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06036945 A	02-1994	Japan	OMURA et al.	H01F 27/28
	O	JP 06140250 A	05-1994	Japan	UEMURA et al.	H01F 15/00
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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